

* Vibration test 10 50 10 Hz sweeped in 60 seconds X,Y,Z direction 1 hour each direction Result: No dislodgement of the cell or damage No discontinuity over 10 micro-seconds.

* Soldering per JSTD020C Table 4.1

* Drop Test:

Mounted on board and dropped 5 times from 1m high to concrete floor

Result: NO dislodgement of the cell, No damage to the holders

* Shock Test: Half sine wave acceleration 150G. 6 milli-seconds. X,Y,Z direction 3 times each direction

Result: No dislodgement of cell

No damage to the holder.

* Temperature resistance test: 80°C 168 hours with battery on

Result: Contact resistance—below 100m ohms Insulation resistance—over 100m ohms.

* Temperature shock test: -30°C \leftarrow 80°C 1hours 100cycles

Contact resistance—below 100m ohms Insulation resistance—over 100m ohms

Voltage resistance- No damage.

* ROHS 2 COMPLIANT

AUTH DR. CK. REVISION RECORD Date 2/17/07 DIMENSION .140 WAS .138 ADDED SOLDERING SPEC. T.B. B.S. 4/26/08 MATERIAL WAS UL94V-0 T.B. B.S. 6/27/08 B.S. 4/02/10 ADDED MARKINGS T.B. UPDATED SHOCK TEST FROM 6/28/13 T.B. B.S. MICRO SEC. TO MILLI SEC. REMOVED PAT, PEND, FROM 3/14/14

Zone for adhesive

.433(11.0)
.140 [3.56)
.102 [2.60]

1.154 [29.3]

PATENT NO. 5,922,489

Tolerance	MPD Mem	ory Prote	ction 1	Devices, Inc
(Except as noted)	200 Broad Hollow Road, Farmingdale, New York 11			
decimal			Scale	Drawn By T.S.
±.5 (.020)			2=1	Approved By T.B.
Fractional	Title			
± .8 (.030)	COIN CELL HOLDER			
Angular	Date	Drawing Nu	mber	
± 3°	3/14/14	BA2032SM		

PCB SPACING